INFORMATION DISCLOSURE STATEMENT BY APPLICANT Sheet 1 of 2

Docket No. B0004/7080

Applicant: Jochen Franzen

Serial No: 09/778,654

Filed: February 7, 2001

GRIDLESS TIME-OF-FLIGHT MASS SPECTROMETER FOR ORTHOGONÁÉ For:

ION INJECTION Examiner: Not Yet Assigned

2881 Art Unit:

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INFORMATION DISCLOSURE STATEMENT BY APPLICANT Sheet 2 of 2

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Examiner

Signature

M. El Shammaa

Jochen Franzen
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Crebruary 7, 2001
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